



IPW

Docket No.: 060188-0839

PATENT

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of	:	Customer Number: 20277
Akio MISAKA	:	Confirmation Number: 6593
Application No.: 10/824,529	:	Group Art Unit: 1756
Filed: April 15, 2004	:	Examiner: ROSASCO, STEPHEN D

For: PHOTOMASK, PATTERN FORMATION METHOD USING PHOTOMASK AND MASK  
DATA CREATION METHOD FOR PHOTOMASK

**INFORMATION DISCLOSURE STATEMENT**

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached form PTO-1449. It is respectfully requested that the references be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

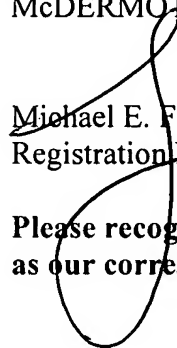
Each non-English language reference was first cited in a corresponding foreign application office action and its relevance discussed therein. A copy of the foreign office action, together with an English language version thereof, is attached for the Examiner's information.

10/824,529

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

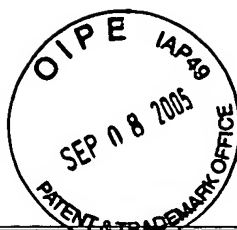
Respectfully submitted,

McDERMOTT WILL & EMERY LLP

  
Michael E. Fogarty  
Registration No. 36,139

600 13<sup>th</sup> Street, N.W.  
Washington, DC 20005-3096  
Phone: 202.756.8000 MEF:gav  
Facsimile: 202.756.8087  
**Date: September 8, 2005**

**Please recognize our Customer No. 20277  
as our correspondence address.**



SHEET 1 OF 1

<b>INFORMATION DISCLOSURE CITATION IN AN APPLICATION</b>  (PTO-1449)				ATTY. DOCKET NO. <b>060188-0839</b>		SERIAL NO. <b>10/824,529</b>	
				APPLICANT <b>Akio MISAKA</b>			
				FILING DATE <b>April 15, 2004</b>		GROUP <b>1756</b>	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code <sup>2</sup> (if known)		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
		US	2003-203290 A1	10/30/2003	Misaka	Corresponds with JP 2004-029747 A	
		US	2003-203291 A1	10/30/2003	Misaka	Corresponds with JP 2004-029746 A	
		US	2004-121244 A1	06/24/2004	Misaka	Corresponds with WO 03/062923 A1	
<b>FOREIGN PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes - Number - Kind Codes (if known)		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation Yes                      No
		JP 2000-019710 A		01/21/2000	HITACHI LTD. HITACHI TOKYO ELECTRONICS CO LTD.		JAPAN (w/English Abstract)
		JP 10-048806		02/20/1998	NEC CORP.		JAPAN (w/English Abstract)
		JP 09-269590		10/14/1997	NEC CORP.		JAPAN (w/English Abstract)
		JP 2004-029747 A		01/29/2004	MATSUSHITA ELECTRIC IND CO LTD.	Corresponds with US 2003-203290 A1	JAPAN (w/English Abstract)
		JP 2004-029746 A		01/29/2004	MATSUSHITA ELECTRIC IND CO LTD.	Corresponds with US 2003-203291 A1	JAPAN (w/English Abstract)
		WO 03/062923 A1		07/31/2003	MATSUSHITA ELECTRIC IND CO LTD.	Corresponds with US 2004-121244 A1	JAPAN (w/English Abstract)
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.					
EXAMINER				DATE CONSIDERED			

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.